

MINOR II
PYL 102: Principles of Electronic Materials
(8 Oct. 2016)

Answer all questions

Time **One Hour**

Maximum Marks **20**

1. State the following statements as True or False with justification (in the absence of justification no marks will be given).
 - (a) Capacitance of a p-n junction increases with the increase of forward bias.
 - (b) In a metal-semiconductor (n-type) junction with $\Phi_M < \chi_S$, cooling effect takes place when current flows from metal to semiconductor.
 - (c) For some metals Seebeck Coefficient is positive and for some metal Seebeck Coefficient is negative.
 - (d) For phonons the group velocity is maximum at $k = \pi/a$.
 - (e) Light absorption by an indirect band gap semiconductor involves photon and phonon. [1 x 5]
2.
 - (a) A metal plate is heated at one end. The temperature of hot and cold end of the metal plate is 100°C and 10°C . What is the voltage developed across the metal plate (Seebeck coefficient, $S = 1.7T \mu\text{V}$, here T is temperature in the unit K). [2]
 - (b) Dispersion relation for phonon is given as $\omega = vk$, where v is sound velocity. Obtain volume (in k space) of one state and density of states $[D(\omega)]$ for phonons. [3]
3. Draw the following (Drawing should be properly labelled)
 - (a) Energy level diagram of metal-n-semiconductor with ($\Phi_M < \chi_S$).
 - (b) I-V characteristics of a p-n junction of a semiconductor (band gap $\sim 3\text{eV}$) in dark and under illumination. (source wave length $\lambda = 700\text{nm}$)
 - (c) I-V characteristics (in the reverse bias region) of a Zener Diode and a tunnel diode).
 - (d) Energy level diagram of tunnel diode when it is biased at the negative resistance region.
 - (e) Energy level diagram of Zener Diode when it is forward bias. [1 x 5]
4. n-and p-type of Silicon (bandgap $\sim 1.1\text{eV}$) are fabricated by doping Arsenic ($N_D = 10^{16}/\text{cm}^3$) and Boron ($N_A = 10^{17}/\text{cm}^3$). A p-n junction is fabricated from these n-and p-type semiconductor. Obtain
 - (a) Positions of Fermi levels for n-and p-semiconductor with reference to Fermi levels of intrinsic semiconductor before the junction is fabricated.
 - (b) After the p-n junction is fabricated, draw the energy level diagram and obtain the built in voltage at the interface.
 - (c) Difference between E_{Fn} and E_{Fp} when 0.2V forward bias is applied at p-n junction.
 $[n_i = 10^{10}\text{cm}^{-3}, T = 300\text{K}, k_B = 8.6 \times 10^{-5}\text{eV K}^{-1}]$ [2+2+1]